| Search | Notes | |
|--------|-------|--|
| | | |
| | | |

| Application/Control No. | Applicant(s)/Patent under Reexamination | |
|-------------------------|---|---|
| 10/531,329 | HIRANUMA ET AL. | • |
| Examiner | Art Unit | |
| Diem Tran | 3748 | |

| | | SEAR | CHÉD | | | |
|------|------|------------------|------|----------|----------|------|
| Cla | ISS | Subclass | Da | ate | Exam | iner |
| | | | | | | |
| 6 | 0 | 276 | 1/5 | /07 | <u> </u> | T |
| | | 295 | , | | | |
| | | 297 | | | | |
| | | 311 | | <i>(</i> | _ | |
| upda | ated | search | 6/14 | 1/07 | D | τ |
| upda | ated | search search | 12/5 | 107 | D | Γ |
| | | | | • | | |
| | | | | | | |
| | | • | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |

| INTERFERENCE SEARCHED | | | |
|-----------------------|----------|------|----------|
| Class | Subclass | Date | Examiner |
| | | | |
| | | | |
| | | • | |
| | - | | <u> </u> |
| | | | |

| DATE | EXMR |
|-------------|------|
| | |
| | |
| | |
| | |
| | |
| | |
| | |
| | |
| | |
| | |
| | |
| | |
| 1 | |
| | |
| | · |
| | |
| | |
| | |
| | |
| | |
| | |
| į | |
| | |
| | |
| | |